

Search Notes

Application No.

09/740,901

Examiner

Mary C Hogan

Applicant(s)

KIDERA ET AL.

Art Unit

2123

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
toshiba.as. and hidetuki.in. : east, ACM, IEEE	11/16/2004	MCH
EAST: conner model, parameter, process, variation, semiconductor, circuit	11/16/2004	MCH
IEEE: 'corner model'<and>'process parameter'<and>'semiconductor ACM: +"corner model" "electrical characteristic" "process para	11/16/2004	MCH
Google: "corner model" process condition simulation parameter	11/16/2004	MCH